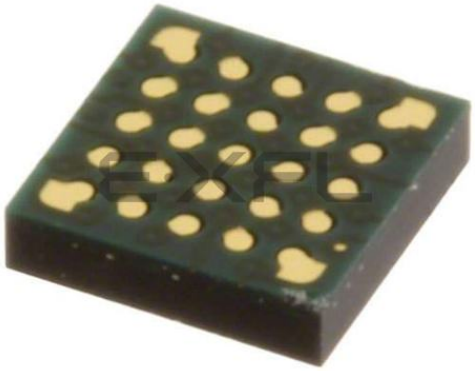


Welcome to E-XFL.COM

What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	RL78
Core Size	16-Bit
Speed	32MHz
Connectivity	CSI, I²C, LINbus, UART/USART
Peripherals	DMA, LVD, POR, PWM, WDT
Number of I/O	14
Program Memory Size	48KB (48K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	3K x 8
Voltage - Supply (Vcc/Vdd)	1.6V ~ 3.6V
Data Converters	A/D 13x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	25-WFLGA
Supplier Device Package	25-LGA (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/renesas-electronics-america/r5f10e8dala-u0

○ ROM, RAM capacities

Flash ROM	Data flash	RAM	RL78/G1A			
			25 pins	32 pins	48 pins	64 pins
64 KB	4 KB	4 KB Note	R5F10E8E	R5F10EBE	R5F10EGE	R5F10ELE
48 KB	4 KB	3 KB	R5F10E8D	R5F10EBD	R5F10EGD	R5F10ELD
32 KB	4 KB	2 KB	R5F10E8C	R5F10EBC	R5F10EGC	R5F10ELC
16 KB	4 KB	2 KB	R5F10E8A	R5F10EBA	R5F10EGA	–

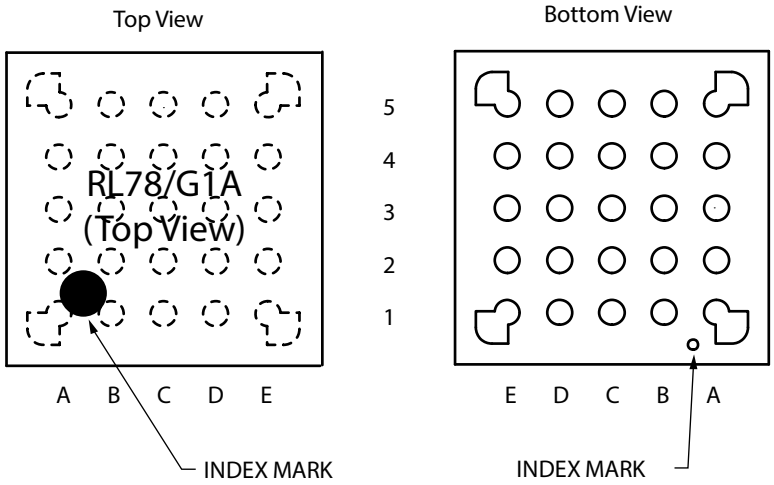
Note This is about 3 KB when the self-programming function and data flash function are used. (For details, see **3. ELECTRICAL SPECIFICATIONS (G: INDUSTRIAL APPLICATIONS T_A = –40 to +105°C)**)

1.3 Pin Configuration (Top View)

1.3.1 25-pin products

- 25-pin plastic WFLGA (3 × 3 mm, 0.50 mm pitch)

<R>



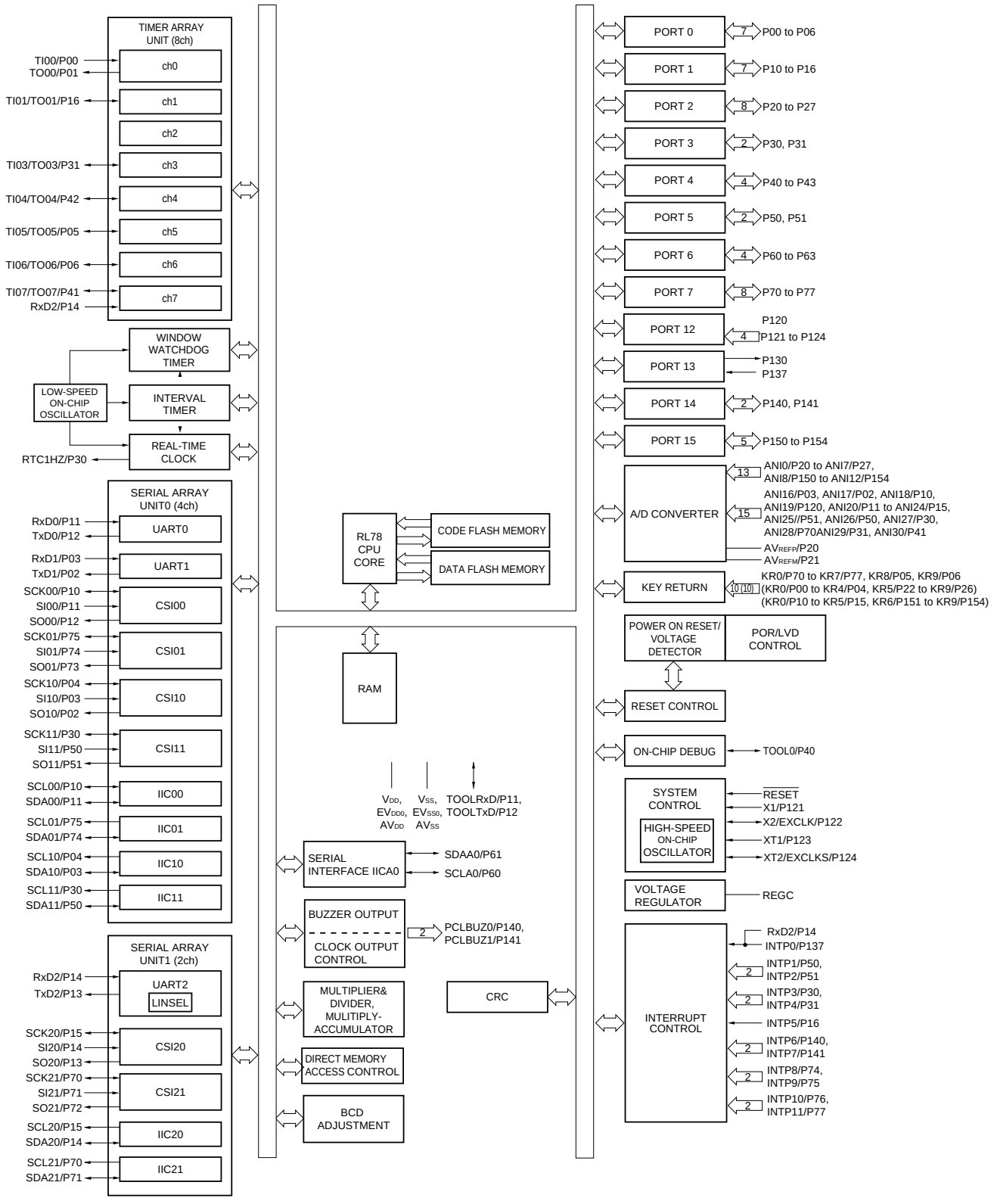
	A	B	C	D	E	
5	P40/TOOL0	$\overline{\text{RESET}}$	P03/ANI16/ RxD1/TO00/ (KR1)	P23/ANI3/ (KR3)	AV_{SS}	5
4	P122/X2/ EXCLK	P137/INTP0	P02/ANI17/ TxD1/TI00/ (KR0)	P22/ANI2/ (KR2)	AV_{DD}	4
3	P121/X1	V_{DD}	P21/ANI1/ AV_{REFM}	P11/ANI20/ SI00/SDA00/ RxD0/ TOOLRxD	P10/ANI18/ SCK00/SCL00	3
2	REGC	V_{SS}	P30/ANI27/ SCK11/SCL11/ INTP3	P51/ANI25/ SO11/INTP2	P50/ANI26/ SI11/SDA11 INTP1	2
1	P60/SCLA0	P61/SDAA0	P31/ANI29/TI03/ TO03/PCLBUZ0 /INTP4	P12/ANI21/ SO00/TxD0/ TOOLTxD	P20/ANI0/ AV_{REFP}	1
	A	B	C	D	E	

Caution Connect the REGC pin to Vss via a capacitor (0.47 to 1 μF).

Remarks 1. For pin identification, see **1.4 Pin Identification**.

2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.5.4 64-pin products



Remark Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

(T_A = –40 to +85°C, 1.6 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V) **(2/3)**

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current[Note 1]	I_{DD2}[Note 2]	HALT mode	HS (high-speed main) mode[Note 7]	f_{IH} = 32 MHz[Note 4]	V_{DD} = 3.0 V		0.54	1.63	mA
				f_{IH} = 24 MHz[Note 4]	V_{DD} = 3.0 V		0.44	1.28	mA
				f_{IH} = 16 MHz[Note 4]	V_{DD} = 3.0 V		0.40	1.00	mA
			LS (low-speed main) mode[Note 7]	f_{IH} = 8 MHz[Note 4]	V_{DD} = 3.0 V		270	530	μA
					V_{DD} = 2.0 V		270	530	
			LV (Low-voltage main) mode[Note 7]	f_{IH} = 4 MHz[Note 4]	V_{DD} = 3.0 V		435	640	μA
					V_{DD} = 2.0 V		435	640	
			HS (high-speed main) mode[Note 7]	f_{MX} = 20 MHz[Note 3], V_{DD} = 3.0 V	Square wave input		0.28	1.00	mA
					Resonator connection		0.45	1.17	
				f_{MX} = 10 MHz[Note 3], V_{DD} = 3.0 V	Square wave input		0.19	0.60	mA
					Resonator connection		0.26	0.67	
			LS (low-speed main) mode[Note 7]	f_{MX} = 8 MHz[Note 3], V_{DD} = 3.0 V	Square wave input		95	330	μA
					Resonator connection		145	380	
				f_{MX} = 8 MHz[Note 3], V_{DD} = 2.0 V	Square wave input		95	330	μA
					Resonator connection		145	380	
			Subsystem clock mode	f_{SUB} = 32.768 kHz[Note 5] T_A = –40°C	Square wave input		0.25	0.57	μA
					Resonator connection		0.44	0.76	
				f_{SUB} = 32.768 kHz[Note 5] T_A = +25°C	Square wave input		0.30	0.57	μA
					Resonator connection		0.49	0.76	
				f_{SUB} = 32.768 kHz[Note 5] T_A = +50°C	Square wave input		0.38	1.17	μA
					Resonator connection		0.57	1.36	
				f_{SUB} = 32.768 kHz[Note 5] T_A = +70°C	Square wave input		0.52	1.97	μA
					Resonator connection		0.71	2.16	
				f_{SUB} = 32.768 kHz[Note 5] T_A = +85°C	Square wave input		0.97	3.37	μA
					Resonator connection		1.16	3.56	
	I_{DD3}[Note 6]	STOP mode[Note 8]	T_A = –40°C				0.16	0.50	μA
			T_A = +25°C				0.23	0.50	
			T_A = +50°C				0.34	1.10	
			T_A = +70°C				0.46	1.90	
			T_A = +85°C				0.75	3.30	

(**Notes** and **Remarks** are listed on the next page.)

(8) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output) (2/2)

(T_A = –40 to +85°C, 1.8 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions	HS[Note 1]		LS[Note 2]		LV[Note 3]		Unit
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SIp setup time (to SCKp↑)[Note 4]	t_{SIK1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	177		479		479		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ	479		479		479		ns
SIp hold time (from SCKp↑)[Note 4]	t_{KSI1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	19		19		19		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ	19		19		19		ns
Delay time from SCKp↓ to SOp output[Note 4]	t_{KSO1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		195		195		195	ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ		483		483		483	ns
SIp setup time (to SCKp↓)[Note 5]	t_{SIK1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	44		110		110		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ	110		110		110		ns
SIp hold time (from SCKp↓)[Note 5]	t_{KSI1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ	19		19		19		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ	19		19		19		ns
Delay time from SCKp↑ to SOp output[Note 5]	t_{KSO1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ		25		25		25	ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 6], C_b = 30 pF, R_b = 5.5 kΩ		25		25		25	ns

Notes 1. HS is condition of HS (high-speed main) mode.

2. LS is condition of LS (low-speed main) mode.

3. LV is condition of LV (low-voltage main) mode.

4. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

5. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

6. Use it with $EV_{DD0} \geq V_b$.

Caution Select the TTL input buffer for the SIp pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SOp pin and SCKp <R> **pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.**

(**Remarks** are listed on the next page.)

(9) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (slave mode, SCKp... external clock input)
(T_A = –40 to +85°C, 1.8 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions		HS[Note 1]		LS[Note 2]		LV[Note 3]		Unit
				MIN.	MAX.	MIN.	MAX.	MIN.	MAX.	
SCKp cycle time[Note 4]	t_{KCY2}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V	24 MHz < f_{MCK}	20/f_{MCK}		–		–		ns
			20 MHz < f_{MCK} ≤ 24 MHz	16/f_{MCK}		–		–		ns
			16 MHz < f_{MCK} ≤ 20 MHz	14/f_{MCK}		–		–		ns
			8 MHz < f_{MCK} ≤ 16 MHz	12/f_{MCK}		–		–		ns
			4 MHz < f_{MCK} ≤ 8 MHz	8/f_{MCK}		16/f_{MCK}		–		ns
			f_{MCK} ≤ 4 MHz	6/f_{MCK}		10/f_{MCK}		10/f_{MCK}		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 5]	24 MHz < f_{MCK}	48/f_{MCK}		–		–		ns
			20 MHz < f_{MCK} ≤ 24 MHz	36/f_{MCK}		–		–		ns
			16 MHz < f_{MCK} ≤ 20 MHz	32/f_{MCK}		–		–		ns
			8 MHz < f_{MCK} ≤ 16 MHz	26/f_{MCK}		–		–		ns
			4 MHz < f_{MCK} ≤ 8 MHz	16/f_{MCK}		16/f_{MCK}		–		ns
			f_{MCK} ≤ 4 MHz	10/f_{MCK}		10/f_{MCK}		10/f_{MCK}		ns
SCKp high-/low-level width	t_{KH2}, t_{KL2}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V		t_{KCY2}/2 – 18		t_{KCY2}/2 – 50		t_{KCY2}/2 – 50		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 5]		t_{KCY2}/2 – 50		t_{KCY2}/2 – 50		t_{KCY2}/2 – 50		ns
SIp setup time (to SCKp↑)[Note 6]	t_{SIK2}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V		1/f_{MCK} + 20		1/f_{MCK} + 30		1/f_{MCK} + 30		ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 5]		1/f_{MCK} + 30		1/f_{MCK} + 30		1/f_{MCK} + 30		ns
SIp hold time (from SCKp↑)[Note 6]	t_{KSI2}			1/f_{MCK} + 31		1/f_{MCK} + 31		1/f_{MCK} + 31		ns
Delay time from SCKp↓ to SOp output[Note 7]	t_{KSO2}	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V, C_b = 30 pF, R_b = 2.7 kΩ			2/f_{MCK} + 214		2/f_{MCK} + 573		2/f_{MCK} + 573	ns
		1.8 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V[Note 5], C_b = 30 pF, R_b = 5.5 kΩ			2/f_{MCK} + 573		2/f_{MCK} + 573		2/f_{MCK} + 573	ns

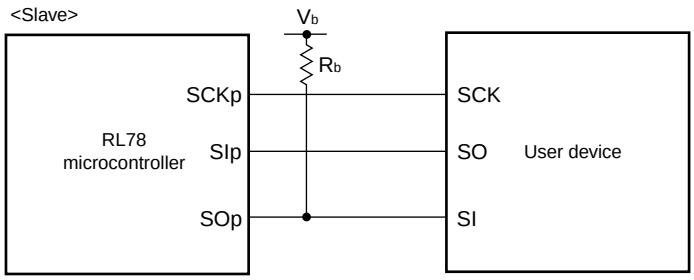
Notes 1. HS is condition of HS (high-speed main) mode.
2. LS is condition of LS (low-speed main) mode.
3. LV is condition of LV (low-voltage main) mode.
4. Transfer rate in the SNOOZE mode : MAX. 1 Mbps
5. Use it with EV_{DD0} ≥ V_b.
6. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.
7. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the SIp pin and SCKp pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

<R>

(**Remarks** are listed on the next page.)

CSI mode connection diagram (during communication at different potential)



Remarks 1. R_b[Ω]: Communication line (SOp) pull-up resistance, C_b[F]: Communication line (SOp) load capacitance, V_b[V]: Communication line voltage

2. p: CSI number (p = 00, 10, 20), m: Unit number (m = 0, 1), n: Channel number (n = 00, 02, 10), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn).
m: Unit number, n: Channel number (mn = 00, 02, 10))

4. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

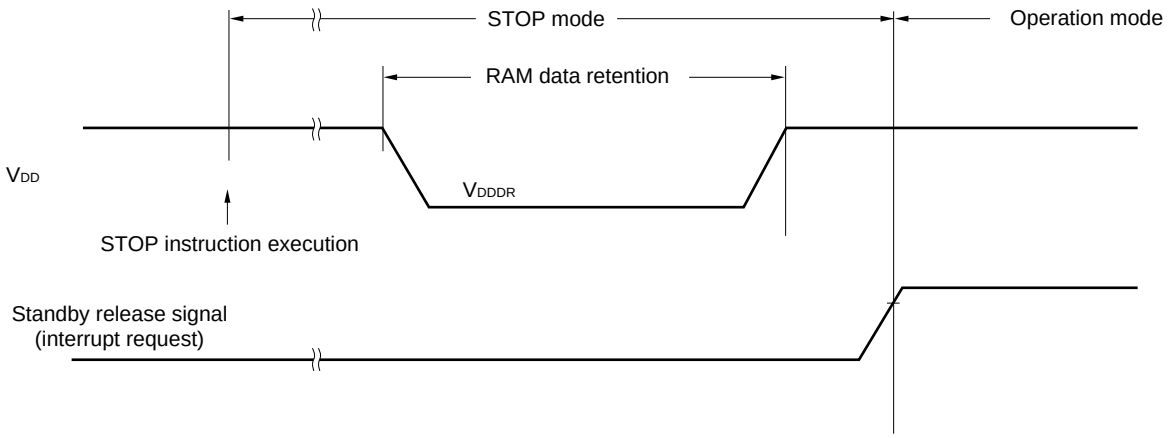
<R> 2.7 RAM Data Retention Characteristics

<R> **(T_A = –40 to +85°C, V_{SS} = 0 V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V_{DDDR}		1.46 Note		3.6	V

<R> **Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.

<R>



<R> 2.8 Flash Memory Programming Characteristics

(T_A = –40 to +85°C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	f_{CLK}	1.8 V ≤ V_{DD} ≤ 3.6 V	1		32	MHz
Number of code flash rewrites Notes 1, 2	C_{erwr}	Retained for 20 years T_A = 85°C Note 3	1,000			Times
Number of data flash rewrites Notes 1, 2		Retained for 1 years T_A = 25°C Note 3		1,000,000		
		Retained for 5 years T_A = 85°C Note 3	100,000			
		Retained for 20 years T_A = 85°C Note 3	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.
The retaining years are until next rewrite after the rewrite.

2. When using flash memory programmer and Renesas Electronics self programming library

3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

(T_A = –40 to +105°C, 2.4 V ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V) **(5/5)**

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input leakage current, high	I_{LIH1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P63, P70 to P77, P120, P140, P141	V_I = EV_{DD0}				1	μA
	I_{LIH2}	P137, $\overline{\text{RESET}}$	V_I = V_{DD}				1	μA
	I_{LIH3}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	V_I = V_{DD}	In input port or external clock input			1	μA
				In resonator connection			10	μA
	I_{LIH4}	P20 to P27, P150 to P154	V_I = AV_{DD}				1	μA
Input leakage current, low	I_{LIL1}	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P60 to P67, P70 to P77, P120, P140, P141	V_I = EV_{SS0}				–1	μA
	I_{LIL2}	P137, $\overline{\text{RESET}}$	V_I = V_{SS}				–1	μA
	I_{LIL3}	P121 to P124 (X1, X2, XT1, XT2, EXCLK, EXCLKS)	V_I = V_{SS}	In input port or external clock input			–1	μA
				In resonator connection			–10	μA
	I_{LIL4}	P20 to P27, P150 to P154	V_I = AV_{SS}				–1	μA
On-chip pull-up resistance	R_U	P00 to P06, P10 to P16, P30, P31, P40 to P43, P50, P51, P70 to P77, P120, P140, P141	V_I = EV_{SS0}, In input port		10	20	100	kΩ

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

Notes 1. Total current flowing into V_{DD} and EV_{DD0}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, EV_{DD0} or V_{SS}, EV_{SS0}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the A/D converter, LVD circuit, I/O port, on-chip pull-up/pull-down resistors, and data flash rewriting.

2. When high-speed on-chip oscillator and subsystem clock are stopped.

3. When high-speed system clock and subsystem clock are stopped.

4. When high-speed on-chip oscillator and high-speed system clock are stopped. When setting ultra-low power consumption oscillation (AMPHS1 = 1). Not including the current flowing into the RTC, 12-bit interval timer and watchdog timer

5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: V_{DD} = 2.7 V to 3.6 V@1 MHz to 32 MHz
V_{DD} = 2.4 V to 3.6 V@1 MHz to 16 MHz

Remarks 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

2. f_{IH}: High-speed on-chip oscillator clock frequency

3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

4. Except subsystem clock operation, temperature condition of the TYP. value is T_A = 25°C

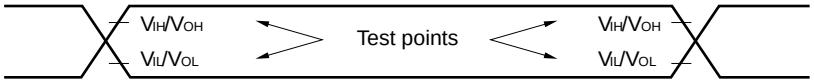
(T_A = –40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V) **(3/3)**

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	I_{FIL} Note 1				0.20		μA
RTC operating current	I_{RTC} Notes 1, 2, 3				0.02		μA
12-bit interval timer operating current	I_{IT} Notes 1, 2, 4				0.02		μA
Watchdog timer operating current	I_{WDT} Notes 1, 2, 5	f_{IL} = 15 kHz			0.22		μA
A/D converter operating current	I_{ADC} Notes 6, 7	AV_{DD} = 3.0 V, When conversion at maximum speed			420	720	μA
$AV_{REF(+)}$ current	I_{AVREF} Note 8	AV_{DD} = 3.0 V, ADREFP1 = 0, ADREFP0 = 0 Note 7			14.0	25.0	μA
		AV_{REFP} = 3.0 V, ADREFP1 = 0, ADREFP0 = 1 Note 10			14.0	25.0	μA
		ADREFP1 = 1, ADREFP0 = 0 Note 1			14.0	25.0	μA
A/D converter reference voltage current	I_{ADREF} Notes 1, 9	V_{DD} = 3.0 V			75.0		μA
Temperature sensor operating current	I_{TMPS} Note 1	V_{DD} = 3.0 V			75.0		μA
LVD operating current	I_{LVD} Notes 1, 11				0.08		μA
BGO operating current	I_{BGO} Notes 1, 12				2.5	12.2	mA
Self-programming operating current	I_{FSP} Notes 1, 13				2.5	12.2	mA
SNOOZE operating current	I_{SNOZ}	A/D converter operation (AV_{DD} = 3.0 V)	The mode is performed Notes 1, 14		0.50	1.10	mA
			During A/D conversion Note 1		0.60	1.34	mA
			During A/D conversion Note 7		420	720	μA
		CSI/UART operation Note 1			0.70	1.54	mA

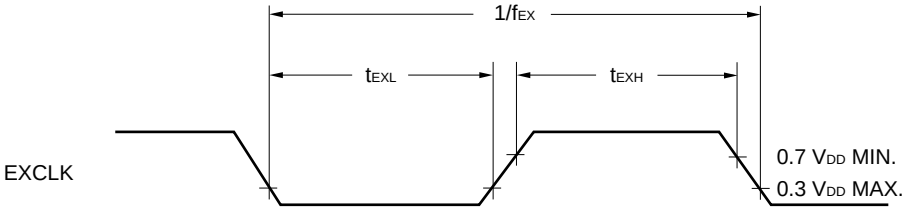
(**Notes** and **Remarks** are listed on the next page.)

AC Timing Test Points

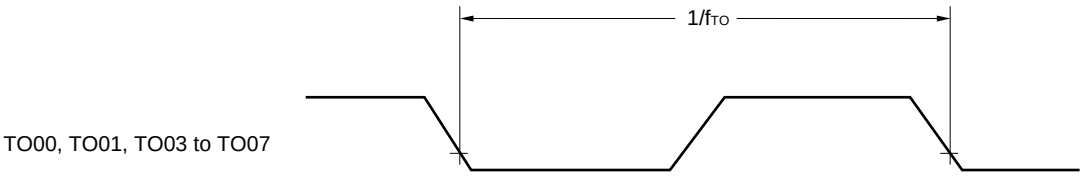
<R>



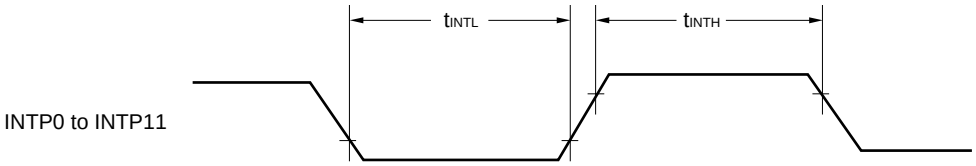
External System Clock Timing



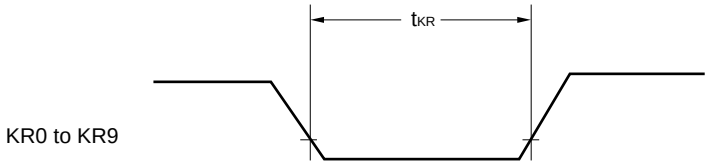
<R> TI/TO Timing



Interrupt Request Input Timing



Key Interrupt Input Timing



(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)

(T_A = –40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
SCKp cycle time	t_{KCY1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V	t_{KCY1} ≥ 4/f_{CLK}	250			ns
		2.4 V ≤ EV_{DD0} ≤ 3.6 V	t_{KCY1} ≥ 4/f_{CLK}	500			ns
SCKp high-/low-level width	t_{KH1}, t_{KL1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V		t_{KCY1}/2 – 36			ns
		2.4 V ≤ EV_{DD0} ≤ 3.6 V		t_{KCY1}/2 – 76			ns
SIp setup time (to SCKp↑)[Note 1]	t_{SIK1}	2.7 V ≤ EV_{DD0} ≤ 3.6 V		66			ns
		2.4 V ≤ EV_{DD0} ≤ 3.6 V		113			ns
SIp hold time (from SCKp↑)[Note 1]	t_{KSI1}			38			ns
Delay time from SCKp↓ to SOp output[Note 2]	t_{KSO1}	C = 30 p[Note 3]				50	ns

Notes 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The SIp setup time or SIp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

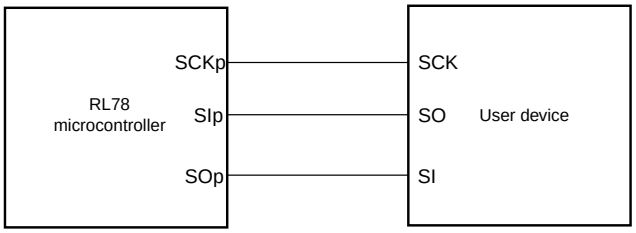
2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

3. C is the load capacitance of the SCKp and SOp output lines.

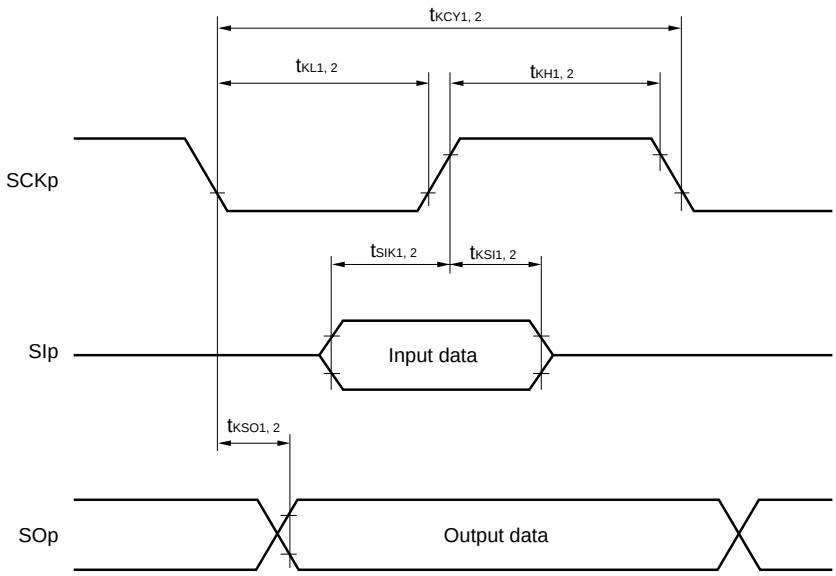
Caution Select the normal input buffer for the SIp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark p: CSI number (p = 00, 01, 10, 11, 20, 21), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM numbers (g = 0, 1)

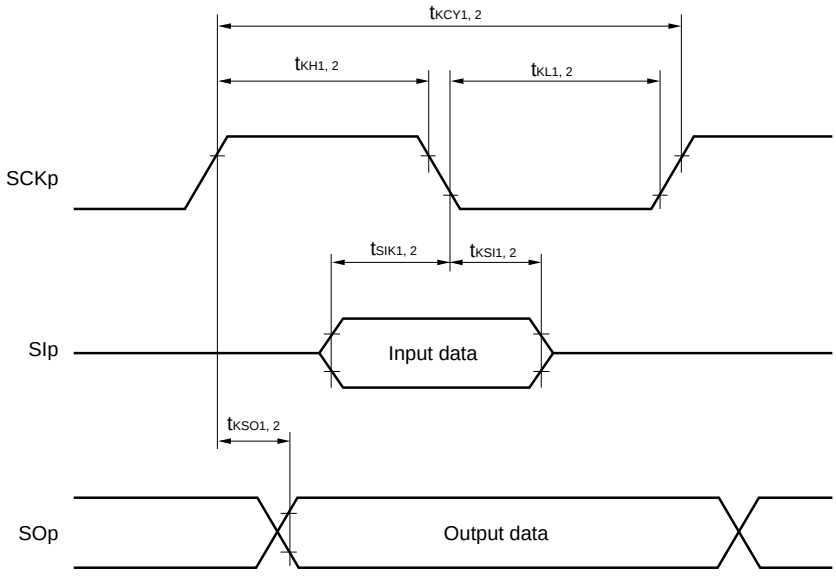
CSI mode connection diagram (during communication at same potential)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remarks 1. p: CSI number (p = 00, 01, 10, 11, 20, 21)

2. m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)

(5) Communication at different potential (1.8 V, 2.5 V) (UART mode) (dedicated baud rate generator output) (1/2)

(T_A = –40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V)

Parameter	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Transfer rate[Note 1]		Reception	2.7 V ≤ EV_{DD0} ≤ 3.6 V, 2.3 V ≤ V_b ≤ 2.7 V				f_{MCK}/12	bps
				Theoretical value of the maximum transfer rate f_{CLK} = 32 MHz, f_{MCK} = f_{CLK}			2.6	Mbps
			2.4 V ≤ EV_{DD0} < 3.3 V, 1.6 V ≤ V_b ≤ 2.0 V				f_{MCK}/12	bps
				Theoretical value of the maximum transfer rate f_{CLK} = 32 MHz, f_{MCK} = f_{CLK}			2.6[Note 2]	Mbps

Notes 1. Transfer rate in the SNOOZE mode is 4800 bps.

2. The following conditions are required for low-voltage interface when EV_{DD0} < V_{DD}.
2.4 V ≤ EV_{DD0} < 2.7 V : MAX. 1.3 Mbps

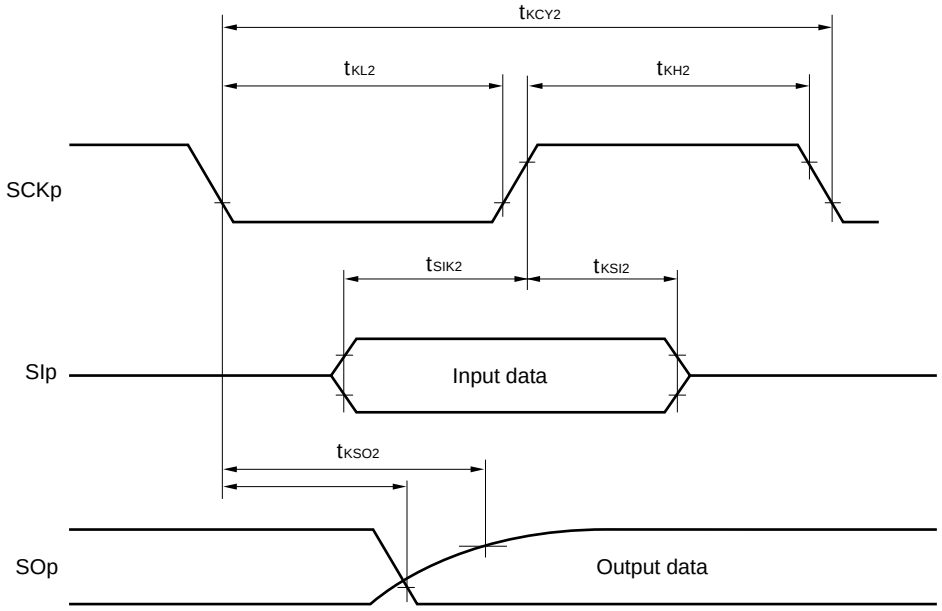
Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance (When 25- to 48-pin products)/EV_{DD} tolerance (When 64-pin products)) mode for the TxDq pin by using <R> **port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.**

Remarks 1. V_b[V]: Communication line voltage

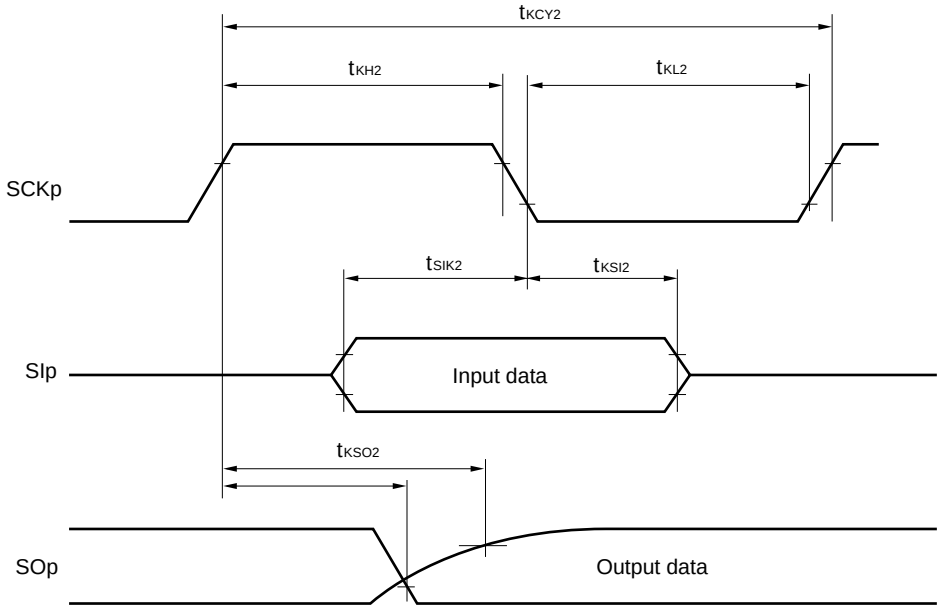
2. q: UART number (q = 0 to 2), g: PIM and POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10, 11)

CSI mode serial transfer timing (slave mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



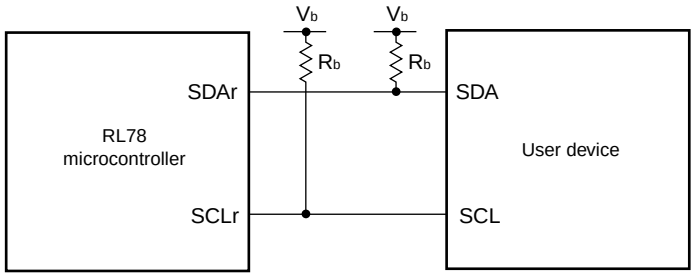
CSI mode serial transfer timing (slave mode) (during communication at different potential)
(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



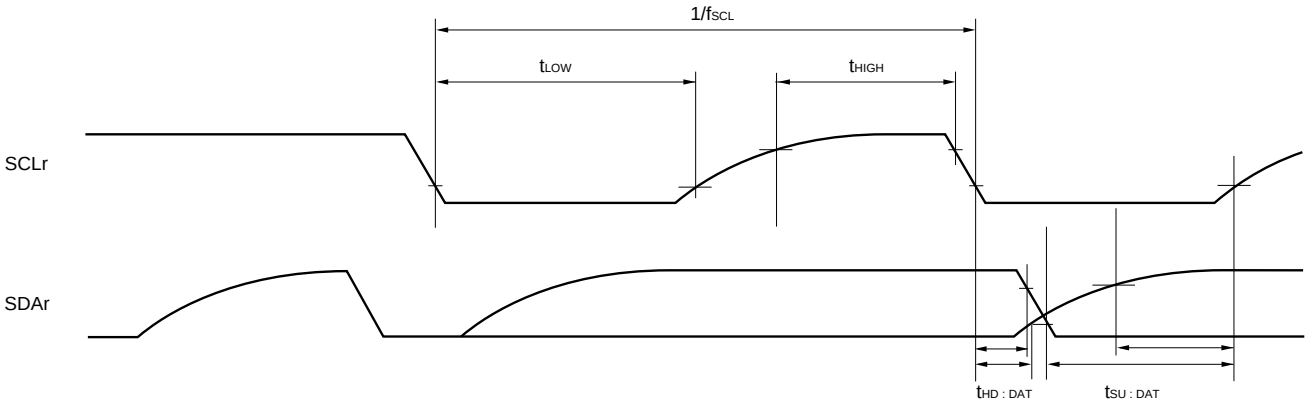
Remarks 1. p: CSI number (p = 00, 10, 20), m: Unit number, n: Channel number (mn = 00, 02, 10), g: PIM and POM number (g = 0, 1)

2. CSI01, CSI11, and CSI21 cannot communicate at different potential. Use other CSI for communication at different potential.

Simplified I^2C mode connection diagram (during communication at different potential)



Simplified I^2C mode serial transfer timing (during communication at different potential)



Remarks 1. R_b[Ω]: Communication line (SDAr, SCLr) pull-up resistance, C_b[F]: Communication line (SDAr, SCLr) load capacitance, V_b[V]: Communication line voltage

2. r: IIC number (r = 00, 10, 20), g: PIM, POM number (g = 0, 1)

3. f_{MCK}: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10)

4. IIC01, IIC11, and IIC21 cannot communicate at different potential. Use IIC00, IIC10, or IIC20 for communication at different potential.

3.6 Analog Characteristics

3.6.1 A/D converter characteristics

Division of A/D Converter Characteristics

Reference voltag / Input channel	Reference voltage (+) = AV_{REFP} Reference voltage (–) = AV_{REFM}	Reference voltage (+) = AV_{DD} Reference voltage (–) = AV_{SS}	Reference voltage (+) = Internal refrence voltage Reference voltage (–) = AV_{SS}
High-accuracy channel; ANI0 to ANI12 (input buffer power supply: AV_{DD})	See **3.6.1 (1)**	See **3.6.1 (2)**	See **3.6.1 (5)**
Standard channel; ANI16 to ANI30 (input buffer power supply: V_{DD} or EV_{DD0})	See **3.6.1 (3)**	See **3.6.1 (4)**	
Temperature sensor, internal reference voltage output	See **3.6.1 (3)**	See **3.6.1 (4)**	–

<R> **(1) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target for conversion: ANI2 to ANI12**

(T_A = –40 to +105°C, 2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V, AV_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	R_{ES}		2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V	8.		12.	bit
Overall error[Note]	AINL	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±6.0	LSB
Conversion time	t_{CONV}	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V	3.375			μs
Zero-scale error[Note]	E_{ZS}	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±4.5	LSB
Full-scale error[Note]	E_{FS}	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±4.5	LSB
Integral linearity error[Note]	ILE	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±2.0	LSB
Differential linearity error[Note]	DLE	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±1.5	LSB
Analog input voltage	V_{AIN}			0		AV_{REFP}	V

Note Excludes quantization error (±1/2 LSB).

<R> **(3) When reference voltage (+) = AV_{REFP}/ANI0 (ADREFP1 = 0, ADREFP0 = 1), reference voltage (–) = AV_{REFM}/ANI1 (ADREFM = 1), target for conversion: ANI16 to ANI30, interanal reference voltage, temperature sensor output voltage**

(T_A = –40 to +105°C, 2.4 V ≤ EV_{DD0} ≤ V_{DD} ≤ 3.6 V, 2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, V_{SS} = EV_{SS0} = 0 V, AV_{SS} = 0 V, Reference voltage (+) = AV_{REFP}, Reference voltage (–) = AV_{REFM} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Resolution	R_{ES}		2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V	8		12	bit
Overall error[Note 1]	AINL	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±7.0	LSB
Conversion time	t_{CONV}	ADTYP = 0, 12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V	4.125			μs
Zero-scale error[Note 1]	E_{ZS}	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±5.0	LSB
Full-scale error[Note 1]	E_{FS}	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±5.0	LSB
Integral linearity error[Note 1]	ILE	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±3.0	LSB
Differential linearity error[Note 1]	DLE	12-bit resolution	2.4 V ≤ AV_{REFP} ≤ AV_{DD} ≤ 3.6 V			±2.0	LSB
Analog input voltage	V_{AIN}			0.		AV_{REFP} and EV_{DD0}	V
		Interanal reference voltage (2.4 V ≤ V_{DD} ≤ 3.6 V, HS (high-speed main) mode)		V_{BGR}[Note 2]			V
		Temperature sensor output voltage (2.4 V ≤ V_{DD} ≤ 3.6 V, HS (high-speed main) mode)		V_{TMPS25}[Note 2]			V

Notes 1. Excludes quantization error (±1/2 LSB).

2. See **3.6.2 Temperature sensor, internal reference voltage output characteristics**.

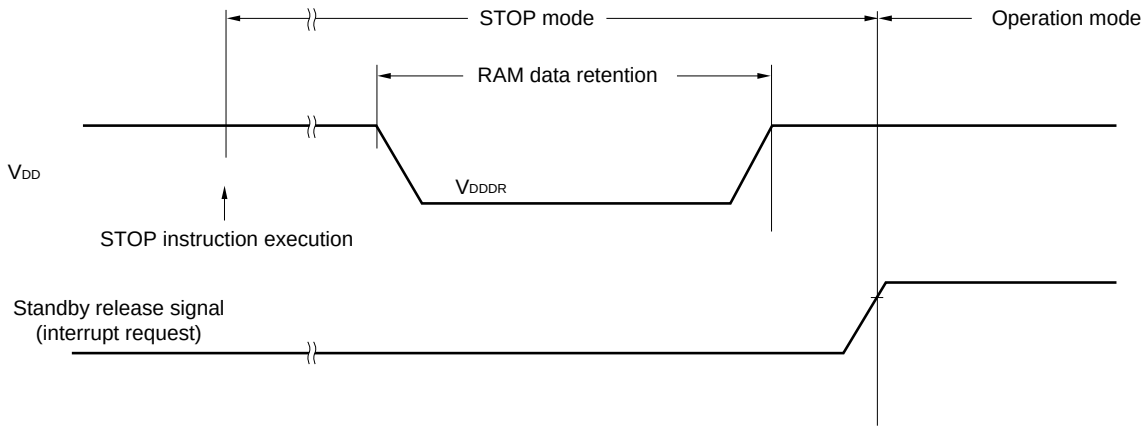
<R> 3.7 RAM Data Retention Characteristics

<R> **(T_A = –40 to +105°C, V_{SS} = 0 V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	V_{DDDR}		1.44[Note]		3.6	V

<R> **Note** This depends on the POR detection voltage. For a falling voltage, data in RAM are retained until the voltage reaches the level that triggers a POR reset but not once it reaches the level at which a POR reset is generated.

<R>



3.8 Flash Memory Programming Characteristics

(T_A = –40 to +105°C, 2.4 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
CPU/peripheral hardware clock frequency	f_{CLK}	2.4 V ≤ V_{DD} ≤ 3.6 V	1		32	MHz
Number of code flash rewrites[Notes 1, 2, 3]	C_{erwr}	Retained for 20 years T_A = 85°C	1,000			Times
Number of data flash rewrites[Notes 1, 2, 3]		Retained for 1 years T_A = 25°C		1,000,000		
		Retained for 5 years T_A = 85°C	100,000			
		Retained for 20 years T_A = 85°C	10,000			

Notes 1. 1 erase + 1 write after the erase is regarded as 1 rewrite.
The retaining years are until next rewrite after the rewrite.

2. When using flash memory programmer and Renesas Electronics self programming library

3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

<R> **4.** This temperature is the average value at which data are retained.